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| Notice of References Cited | Application/Control No. 10/601,222 | Applicant(s)/Patent Under Reexamination JEDDELOH ET AL. | |
| | Examiner Michael J. Brown | Art Unit 2116 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | A | US-6,477,614 | 11-2002 | Leddige et al. | 711/5 |
| * | B | US-5,546,591 | 08-1996 | Wurzburg et al. | 713/322 |
| * | C | US-2005/0177755 | 08-2005 | Fung, Henry T. | 713/300 |
| * | D | US-2004/0199730 | 10-2004 | Eggers et al. | 711/154 |
| * | E | US-2004/0024959 | 02-2004 | Taylor, George R. | 711/105 |
| * | F | US-4,641,249 | 02-1987 | Gion et al. | 702/25 |
| * | G | US-6,970,968 | 11-2005 | Holman, Thomas J. | 711/5 |
| * | H | US-5,881,072 | 03-1999 | Dell, Timothy Jay | 714/763 |
| * | I | US-2004/0008545 | 01-2004 | Korotkov et al. | 365/189.05 |
| * | J | US-2004/0047169 | 03-2004 | Lee et al. | 365/063 |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
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| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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